

METHOD FOR EMPLOYING MEMORY WITH DEFECTIVE SECTIONS

Abstract

A method for forming a linked list with defective memory in an electronic device is disclosed. The method includes the steps of: performing at least a built-in self test (BIST) on a memory of the electronic device; and forming or updating the linked list of the electronic device according to at least a result of the BIST; whereby the linked list of the electronic device does not correspond to any defective memory sections.